

Efficient Test Methodologies For High-speed Serial Links

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1; Efficient Test Methodologies for High-Speed Serial Links; 1 1.1; 1 Introduction; 11 1.1.1; 1.1 Overview of High-Speed Serial Links; 11 1.1.1.1; 1.1.1 High-Speed Serial Link System; 11 1.1.1.2; 1.1.2 Testing High-Speed Serial Links; 12 1.1.2; 1.2 Challenges in Testing High-Speed Serial Links; 13 1.1.3; 1.3 Contributions of the Dissertation; 14 1.2; 2 An Efficient Jitter Measurement Technique; 16 1.2.1; 2.1 Comparator Undersampling Technique; 16 1.2.2; 2.2 Random Jitter Measurement; 18 1.2.2.1; 2.2.1 Proposed RJ Measurement Technique; 19 1.2.2.2; 2.2.2 Limitations of the Technique; 21 1.2.3; 2.3 Experimental Results; 22 1.2.3.1; 2.3.1 Simulation Results; 23 1.2.3.1.1; 2.3.1.1 Simulation: Case 1; 23 1.2.3.1.2; 2.3.1.2 Simulation: Case 2; 23 1.2.3.1.3; 2.3.1.3 Simulation: Case 3; 24 1.2.3.2; 2.3.2 Measurement Results; 25 1.2.3.2.1; 2.3.2.1 Experiment: Case 1; 25 1.2.3.2.2; 2.3.2.2 Experiment: Case 2; 26 1.2.4; 2.4 Summary; 27 1.3; 3 BER Estimation for Linear Clock and Data Recovery Circuit; 28 1.3.1; 3.1 BER Analysis with Random Jitter; 29 1.3.1.1; 3.1.1 Error Occurrences; 29 1.3.1.2; 3.1.2 BER Estimation with Random Jitter; 29 1.3.2; 3.2 BER Analysis with Random Jitter and Periodic Jitter; 31 1.3.2.1; 3.2.1 Jitter Transfer Characteristics of a CDR Circuit; 32 1.3.2.2; 3.2.2 BER Estimation with RJ and PJ; 34 1.3.2.2.1; 3.2.2.1 Dual-Dirac Model and Its Modification; 34 1.3.2.2.2; 3.2.2.2 BER Estimation Taking into Account Clock Recovery Function; 35 1.3.3; 3.3 BER Analysis Including Intrinsic Noise in the CDR Circuit; 41 1.3.4; 3.4 Experimental Results; 43 1.3.4.1; 3.4.1 Simulation Results; 43 1.3.4.2; 3.4.2 Hardware Validation Results; 44 1.3.4.2.1; 3.4.2.1 Jitter Transfer Characteristics; 45 1.3.4.2.2; 3.4.2.2 BER Measurement Results; 47 1.3.5; 3.5 Summary and Future Work; 49 1.4; 4 BER Estimation for Non-linear Clock and Data Recovery Circuit; 50 1.4.1; 4.1 Jitter Analysis for BB CDR Circuits; 50 1.4.1.1; 4.1.1 Jitter Transfer Analysis; 51 1.4.1.2; 4.1.2 Jitter Tolerance Analysis; 54 1.4.2; 4.2 BER Estimation; 54 1.4.2.1; 4.2.1 Variation of Jitter Transfer Due to RJ; 55 1.4.2.2; 4.2.2 BER Estimation; 57 1.4.3; 4.3 Experimental Setup and Results; 58 1.4.3.1; 4.3.1 Simulation Setup; 58 1.4.3.2; 4.3.2 Simulation Results; 59 1.4.4; 4.4 Summary; 60 1.5; 5 Gaps in Timing Margining Test; 61 1.5.1; 5.1 Timing Margining Test Basics; 61 1.5.2; 5.2 Gap Analysis in Timing Margining Test; 62 1.5.2.1; 5.2.1 Random Jitter; 63 1.5.2.2; 5.2.2 PLL-Based Clock Recovery with Non-linear Phase Detector; 64 1.5.2.3; 5.2.3 Jitter Amplification; 67 1.5.2.4; 5.2.4 Duty Cycle

Distortion in Clock;69 1.5.3;5.3 Summary and Future Work;71 1.6;6 An Accurate Jitter Estimation Technique;73 1.6.1;6.1 Characteristics of DJ;73 1.6.1.1;6.1.1 ISI-Induced Jitter;74 1.6.1.2;6.1.2 Crosstalk-Induced Jitter;74 1.6.2;6.2 Total Jitter Estimation;76 1.6.2.1;6.2.1 Estimation Based on Dual-Dirac Model;76 1.6.2.2;6.2.2 High-Order Polynomial Fitting;79 1.6.2.3;6.2.3 Accuracy Versus Number of Samples for Fitting;79 1.6.3;6.3 Summary;80 1.7;7 A Two-Tone Test Method for Continuous-Time Adaptive Equalizers;82 1.7.1;7.1 Continuous-Time Adaptive Equalizer;83 1.7.2;7.2 Proposed Two-Tone Test Method;85 1.7.2.1;7.2.1 Description of the Test Method;85 1.7.2.2;7.2.2 Implementation of the Test Method;86 1.7.3;7.3 Experimental Results;89 1.7.3.1;7.3.1 MATLAB Simulation Results;89 1.7.3.2;7.3.2 Transistor-Level Simulation Results;91 1.7.4;7.4 Summary and Future Work;92 1.8;8 Conclusions;95 1.9;A Extracting Effective PJ and RJ Components from Jitter Histogram;97 1.10;References;100 EAN/ISBN : 9789048134434 Publisher(s): Springer Netherlands Format: ePub/PDF Author(s): Hong, Dongwoo - Cheng, Kwang-Ting (Tim)

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